AMENDMENTS TO THE CLAIMS

1. (Currently Amended) A method of testing a memory die, comprising:

testing said memory die; and

~~storing at least a partial memory cell address on said die as a result of said testing act~~ storing in said memory die at least a partial address of any defective memory cell found during said testing, wherein said storing replaces any previously stored address or partial address, said at least a partial address corresponding to a memory cell having failed said testing [[act]],

wherein said testing and storing [[acts]] are performed outside of a production facility of said die.

2. (Currently Amended) The method in claim 1, wherein said testing [[act]] comprises testing said die while said die is part of an electronic system.

3. (Currently Amended) The method in claim 2, wherein said testing [[act]] comprises testing said die while said electronic system is in a power management mode.

4. (Currently Amended) The method in claim 2, wherein said testing [[act]] comprises testing said die while said die is part of a computer system.

5. (Currently Amended) The method in claim 2, wherein said testing [[act]] comprises testing said die while said die is part of a telephone system.

6. (Currently Amended) The method in claim 5, wherein said testing [[act]] comprises testing said die while said die is part of a cellular telephone system.

7-63. (Canceled)

64. (Currently Amended) A method of testing a memory die, comprising:

testing said memory die; and

~~storing at least a partial memory cell address on said die as a result of said testing act~~ storing in said memory die at least a partial address of any defective memory cell found during said testing, wherein said storing replaces any previously stored address or partial address, said at least a partial address corresponding to a memory cell having failed said testing [[act]],

wherein said testing and storing [[acts]] are performed in [[the]] a field.

65. (Currently Amended) A method of testing a memory die, comprising:

testing said memory die; and

~~storing at least a partial memory cell address on said die as a result of said testing act~~ storing in said memory die at least a partial address of any defective memory cell found during said testing, wherein said storing replaces any previously stored address or partial address, said at least a partial address corresponding to a memory cell having failed said testing [[act]],

wherein said testing and storing [[acts]] are performed when said die is part of a processing system.

66. (New) The method of claim 1, wherein said storing in a register at least a partial address of any defective memory cell comprises storing a column address of the defective memory cell.

67. (New) The method of claim 1, wherein said storing in a register at least a partial address of any defective memory cell comprises storing a row address of the defective memory cell.